



AMENDMENTS TO THE SPECIFICATION:

Please amend the paragraph beginning at page 2, line 15, as follows:

Examples of the prior art for detecting the thickness error of the transparent substrate can be have been proposed in Japanese Patent Publication No. 2000-11402 and Japanese Patent Publication No. 2000-20993, which disclose a method for detecting the thickness error of the transparent substrate based on the difference between the focus error signal detected from the light reflecting from the recording surface and the focus error signal detected from the light reflecting from the transparent substrate surface. This method uses [[using]] an optical element that splits a light beam from a single light source into two light beams or two light beams from two light sources to cause these light beams to focus on the recording surface and the transparent substrate surface respectively. Also, Japanese Patent Publication No. 2000-20999 discloses a method for detecting the thickness error of the transparent substrate based on the light intensity distribution obtained by splitting the light beam reflecting reflected from the recording surface through the transparent substrate, spatially offsetting the two light beams, and then overlaying them one on top of the other.

Please amend the paragraph beginning at page 3, line 7, as follows:

However, since all of these prior art methods require special optical systems for detecting the thickness error, they all present a common problem in diminishing productivity and increasing manufacturing costs increase due to the increasing larger number of parts and numbers of work hours required for system adjustments as well as problems of difficulty in designing smaller and lighter optical disk devices due to the need for special optical systems for detecting thickness errors.

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Please amend the paragraph beginning at page 3, line 18, as follows:

The object of the present invention is to provide an optical disk device that enables us to achieves a stable high-density recording/reproduction by means of detecting thickness errors of the transparent substrate and to compensate for spherical aberrations despite an increase in the objective lens' NA without requiring any special optical system[[],]. Thus thus eliminating the chance of any substantial productivity declines or costs increasing, or increasing the size of the device is eliminated.

Please amend the paragraph beginning at page 16, line 27, as follows:

The light reflected on the recording/reproducing surface of the optical disk 7, passes through the transparent substrate 8 again, becomes a parallel light by means of the objective lens 6, is condensed by the collimator lens 3 via the quarter wavelength plate 4 and the spherical aberration compensator 5, and enters the polarizing beam splitter 2. The light beam entering the polarizing beam splitter 2 is reflected by the polarizing beam splitter 2 as its plane of polarization is rotated [[90?]] 90° by passing the quarter wavelength plate 4 twice.

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